STF30N10F7



N-channel 100 V, 0.02 Ω typ., 24 A STripFET™ F7 Power MOSFET in a TO-220FP package

Datasheet - production data

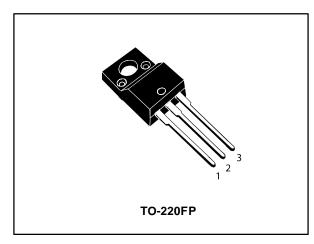
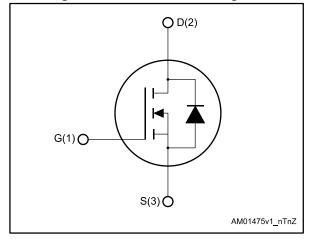


Figure 1: Internal schematic diagram



Features

- Among the lowest R_{DS(on)} on the market
- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low onstate resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

Order code	Marking	Package	Packing
STF30N10F7	30N10F7	TO-220FP	Tube

Contents STF30N10F7

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STF30N10F7 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	100	V
V_{GS}	Gate source voltage	20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	24	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	16	Α
I _{DM} ⁽¹⁾⁽²⁾	Drain current (pulsed)	96	Α
Ртот	Total dissipation at T _C = 25 °C 25		W
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s; T _C =25 °C)		V
TJ	Operating junction temperature range		°C
T _{stg}	Storage temperature range	-55 to 175	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	6	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	62.5	°C/W

⁽¹⁾Current is limited by package.

 $[\]ensuremath{^{(2)}}\mbox{Pulse}$ width limited by safe operating area.

Electrical characteristics STF30N10F7

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4: On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	V _{GS} = 0 V, I _D = 250 μA	100			V
	- · ·	V _{GS} = 0 V , V _{DS} =100 V			1	μΑ
IDSS	Zero gate voltage drain current	V _{GS} = 0 V, V _{DS} =100 V, T _C = 125 °C ⁽¹⁾			100	μΑ
I _{GSS}	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = +20 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2.5		4.5	٧
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 16 A		0.02	0.024	Ω

Notes:

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	1270	ı	pF
Coss	Output capacitance	$V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$		290	•	pF
Crss	Reverse transfer capacitance	1 1 20 00 1,1 1 1 1 1 2,1 00 0 1	-	24	-	pF
Qg	Total gate charge	$V_{DD} = 50 \text{ V}, I_{D} = 32 \text{ A},$	-	19	-	nC
Qgs	Gate-source charge	V _{GS} = 10 V	-	9	-	nC
Q_{gd}	Gate-drain charge	(see Figure 14: "Test circuit for gate charge behavior")	-	4.5	•	nC

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V _{DD} = 50 V, I _D = 16 A,	ı	12	•	ns
tr	Rise time	$R_G = 4.7 \Omega, V_{GS} = 10 V$	-	17.5	•	ns
t _{d(off)}	Turn-off delay time	(see Figure 13: "Test circuit for	-	22	-	ns
tf	Fall time	resistive load switching times")	ı	5.6	1	ns

⁽¹⁾Defined by design, not subject to production test

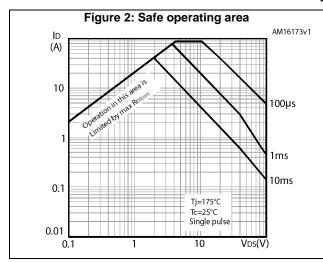
Table 7: Source-drain diode

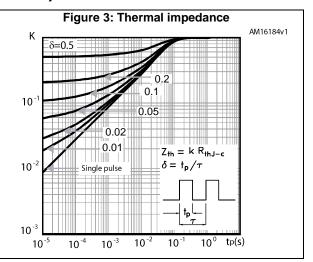
Table 1. Source drain aloue						
Symbol	Parameter	Test conditions		Тур.	Max.	Unit
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} = 24 A, V _{GS} = 0	-		1.1	V
Irr	Reverse recovery time	I _{SD} = 24 A, di/dt = 100 A/μs	ı	41		ns
Qrr	Reverse recovery charge	V _{DD} = 80 V, T _J = 150 °C, (see Figure 15: "Test circuit for inductive load"	ı	47		nC
I _{RRM}	Reverse recovery current	switching and diode recovery times")	-	2.3		Α

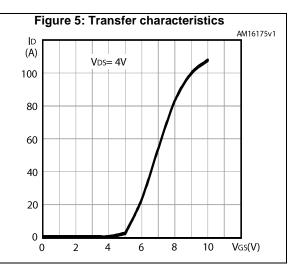
Notes:

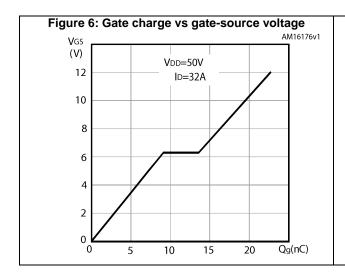
 $^{^{(1)}\}text{Pulsed:}$ pulse duration = 300 $\mu\text{s,}$ duty cycle 1.5%.

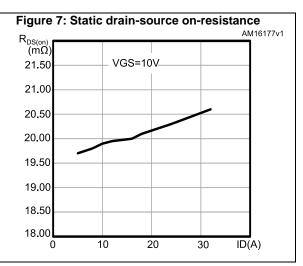
2.1 Electrical characteristics (curves)











STF30N10F7 Electrical characteristics

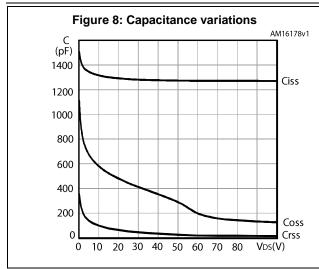


Figure 9: Normalized gate threshold voltage vs temperature

VGS(th) (norm)

1.2

1

0.8

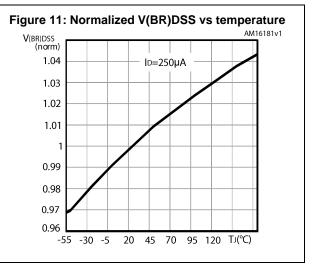
0.6

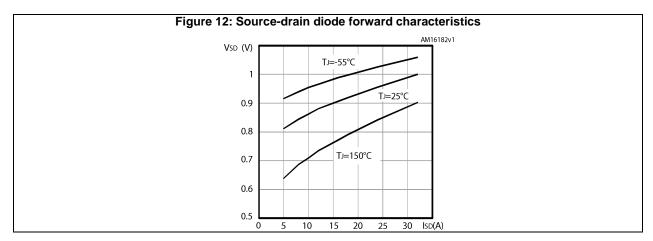
0.4

0.2

0

-55 -30 -5 20 45 70 95 120 145 Τι(°C)





Test circuits STF30N10F7

3 Test circuits

Figure 13: Test circuit for resistive load switching times

Figure 14: Test circuit for gate charge behavior

12 V 47 KΩ 100 Ω D.U.T.

12 V 47 KΩ VGD

14 VGD

15 VGD

16 CONST 100 Ω VGD

17 VGD

18 VGD

18 VGD

18 VGD

18 VGD

19 VGD

19 VGD

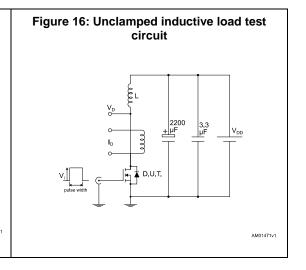
10 VGD

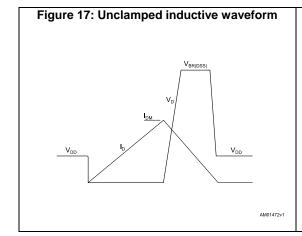
10 VGD

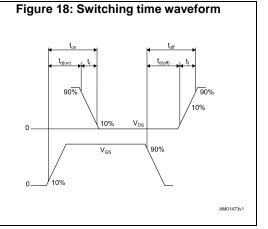
11 KΩ

AM01469v1

Figure 15: Test circuit for inductive load switching and diode recovery times







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STF30N10F7 Package information

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-220FP type A package information

Figure 19: TO-220FP package outline

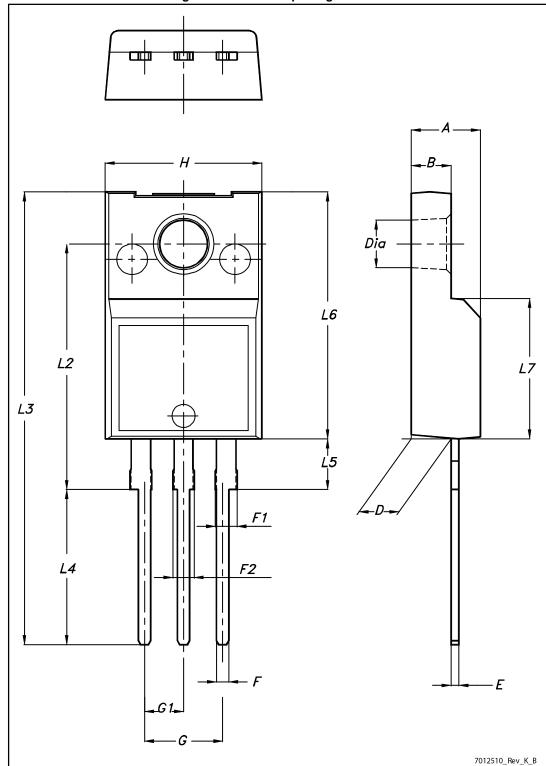


Table 8: TO-220FP package mechanical data

Di	mm		
Dim.	Min.	Тур.	Max.
А	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

Revision history STF30N10F7

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
15-Sep-2016	1	First release.

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